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Texas Instruments Enhanced Products Reliability Report

(Subject To Attached Disclaimers)

Device Type/Device Family:UC2825AQDWREPPackage Type:16 SOIC (Ti Designator DW)Wafer Fabrication Facility:ShermanAssembly/Test Facility:CarsemsCompiled :12/11

Biased Life Test

Test Method: JESD22-A108 Test Condition: 150°/500 hours or Equiv. Sample Size: 8133 Rejects: 0 Activation Energy (eV): .7 Equivalent Device Hours: 26.17E6 Failure Rate (FIT)*: 35.2

*Derated to +55°C with a 60% Confidence Level

Note: Data for EP product is specific to device technology and foundry. For this reason the FIT rate above may differ from Ti's external web page. This does not reflect a difference in quality but only a difference in sample size.

Package Related Tests

Description	<u>Condition</u>	Referenced Method	Sample Size/Rejects	
Biased Humidity or HAST	85°C / 85% / 1000 hours or 130°C / 85% / 96 hours**	JESD22-A101 JESD22-A110	231/0	*
Autoclave	121 °C @ 2 atmospheres absolute for 96 hours	JESD22-A102	231/0	*
Temperature Cycle	-65 °C to +150 °C non-biased for 1000 cycles	JESD22-A104	847/0	*
High Temp Storage	170 °C / 420 hours	JESD22-A103-A	231/0	*

* Preconditioning per JEDEC Std. 22, Method A112/A113 ** This device has been qualified to the elevated standard of 250 Hrs 130/85 HAST (Highly Accelerated Stress Test). This qualification level surpasses JEDEC requirements.



Initial Product Qualification

The subject Enhanced Plastic device, device family, and/or package family have passed Texas Instruments product qualification as follows:

Description	Condition	Sample Size	Referenced Method
Electrical Characterization	TI Data Sheet	50 units/lot	N/A
Electrostatic Discharge Sensitivity	HBM MM	3 units/voltage	EIA/JESD22-A114 EIA/JESD22-A115
Latch-up	Per Technology	5/0 units/lot	EIA/JESD78
Physical Dimensions	TI Data Sheet	5/0	EIA/JESD22- B100
Thermal Impedance	Theta-JA on board	Per Pin-Package	EIA/JESD51
Bias Life Test	125°C / 1000 hours or equivalent	116/0	JESD22-A108 *
Biased Humidity	85°C / 85% / 1000 hours	77/0	JESD22-A101 *
HAST	or 130°C / 85% / 96 hours		JESD22-A110
Autoclave	121 °C @ 2 atmospheres absolute for 96 hours	77/0	JESD22-A102 *
Temperature Cycle	-65 °C to +150 °C non-biased for 1,000 cycles	77/0	JESD22-A104 *
Solder Heat	260 °C for 10 seconds	22/0	JESD22-B106
Resistance to Solvents	Ink symbol only	12/0	JESD22-B107
Solderability	Condition A (steam age for 8 hours)	22/0	ANSI/J-STD-002-92
Flammability	Method A / Method B	5/0	UL-1964
Bond Strength	-	76/0 wires	ASTM F-459
Die Shear	-	5/0	MIL-STD-883 Method 2019
High Temp Storage	150 °C / 1,000 hours	45/0	JESD22-A103-A *
Moisture Sensitivity	Surface Mount Only	12/0	J-STD-020-A * Precondition performed

Supplemental Device Characteristics

	Device Type:	UC2825AMDWREP	
Die Revision:	-	Assembly Site:	CAR
Master Die:	SMJJAC2825IS	Package Type:	SOIC (Ti Designator DW)
Wafer Fab:	SFAB	Pin Count:	16
Fab Technology:	Bipolar	Mold Compound:	SUMITOMO G600C
Fab Process:	Bipolar	Mount Compound:	ABLESTIK 8290
Process Code:	N/A	Bond:	33.0u Au
Passivation:	9KAOX/2KA	Lead Composition:	Cu
Metal 1:	NITRIDE AlCu2	Lead Finish:	NiPdAu
Metal 2:	-	Die Size:	121 X 134 MILS
Metal 2:	-		

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